

**Notice of References Cited**

Application/Control No.

10/573,252

Applicant(s)/Patent Under  
Reexamination  
EBIKO ET AL.

Examiner

THANH C. LE

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2008/0051044	02-2008	Takehara, Hiroyasu	455/127.2
*	B	US-2006/0046764	03-2006	Ohba et al.	455/522
*	C	US-2005/0243909	11-2005	Itahara et al.	375/240
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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